

Specifications

Insulation Resistance



ESD SMD Comm COG, Ceramic, 1,000 pF, 1%, 200 VDC, COG, SMD, MLCC, Temperature Stable, Electro Static Discharge, Class I, 0805, 0.7 mm



| General Information | |
|--------------------------|--|
| Series | ESD SMD Comm COG |
| Style | SMD Chip |
| Description | SMD, MLCC, Temperature Stable, Electro Static Discharge, Class I |
| Features | Temperature Stable, Low ESR, Class I |
| RoHS | Yes |
| Termination | Tin |
| Marking | No |
| AEC-Q200 | No |
| Typical Component Weight | 13 mg |
| Shelf Life | 78 Weeks |
| MSL | 1 |

| Dimensions | |
|------------|-----------------|
| Chip Size | 0805 |
| L | 2mm +/-0.2mm |
| W | 1.25mm +/-0.2mm |
| Т | 0.9mm +/-0.10mm |
| S | 0.7mm MIN |
| В | 0.5mm +/-0.25mm |

| Capacitance | 1,000 pF |
|--|---------------------------|
| Measurement Condition | 1 MHz 1.0Vrms |
| Tolerance | 1% |
| Voltage DC | 200 VDC |
| ESD Level per AEC-Q200 | 8,000 V ESD Level |
| Dielectric Withstanding Voltage | 500 VDC |
| Temperature Range | -55/+125°C |
| Temp. Coefficient | COG |
| | 600 |
| Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC) | 30 ppm/C, 1MegaHz 1.0Vrms |
| Capacitance Change with Reference to +25°C and 0 VDC | |

100 GOhms

| Packaging Specifications | |
|--------------------------|-----------|
| Packaging | Bulk, Bag |
| Packaging Quantity | 1 |

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.

Generated 07/17/2025 © 2006 - 2025 YAGEO